



Sandia  
National  
Laboratories

# Die Attach Epoxy Characterization for Electronic Assemblies

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# Die Attach Epoxy



Thunderbirds 2011

Sandia photographer Randy Montoya captured these photos of the US Air Force's Thunderbirds

**Great things are  
done by a series of  
small things  
brought together**

*Vincent Van Gogh*

# Outline



- Functionality of die attach
- System requirements drive die attach requirements
- Properties measurements
- Conclusions
- Acknowledgements
- Q & A



# Die Attach Functionality

- Semiconductor chips are often attached to substrates, leadframes, ceramics or printed wiring boards with die attach adhesives
- This presentation will cover wire bonded products (no flip chip) and A stage vs B stage die attach materials
- Die attach adhesives are typically **polymer-based composites with non-polymer fillers**
- **Adheres** the silicon to either organic or metal surfaces (Solder mask, Cu, Au, etc.)
- **Accommodates thermal expansion mismatches** between silicon and substrate or leadframe
- Provides a **thermal path**
- Provides **electrical conductivity** per device needs
- Does so **without harming** or contaminating the circuit

# System Requirements Drive Die Attach Requirements

## System Requirements

**Reliability**

**Electrical Performance**

**Manufacturability**

## Die Attach Derived Requirements

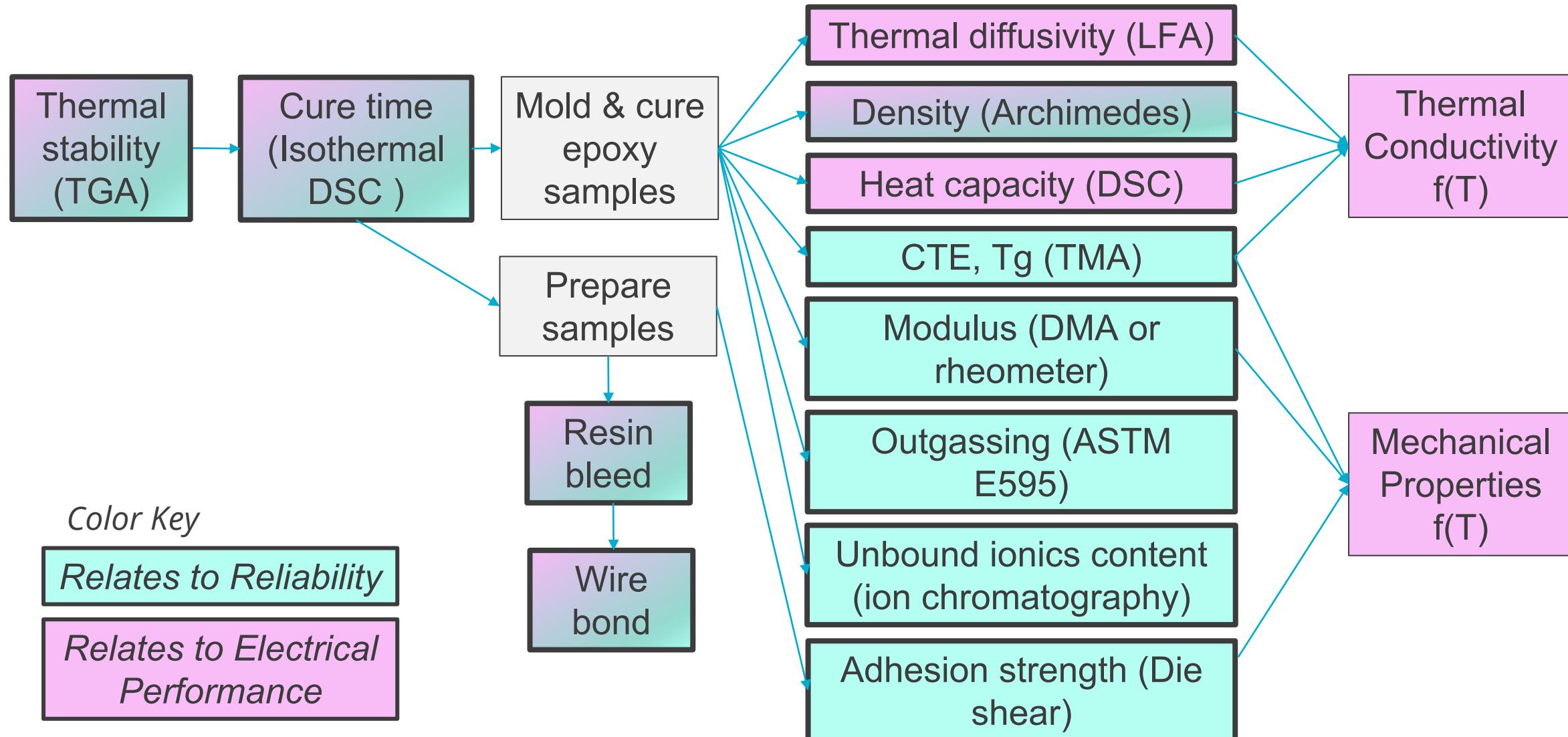
Mechanical properties, Strength and adhesion to interfaces, Contamination (Outgassing, Resin bleed, Ionics) Voiding, Moisture diffusivity, Thermal stability, and Cure parameters

Electrical resistivity, Filler, Thermal conductivity and diffusivity, Heat capacity, Adhesion strength, Voiding

Dispensability & consistency (Viscosity, Thixotropy), Cure conditions, Voiding, Resin bleed, Thermal stability

*System and sub-system requirements are diverse – no single material fits all needs*

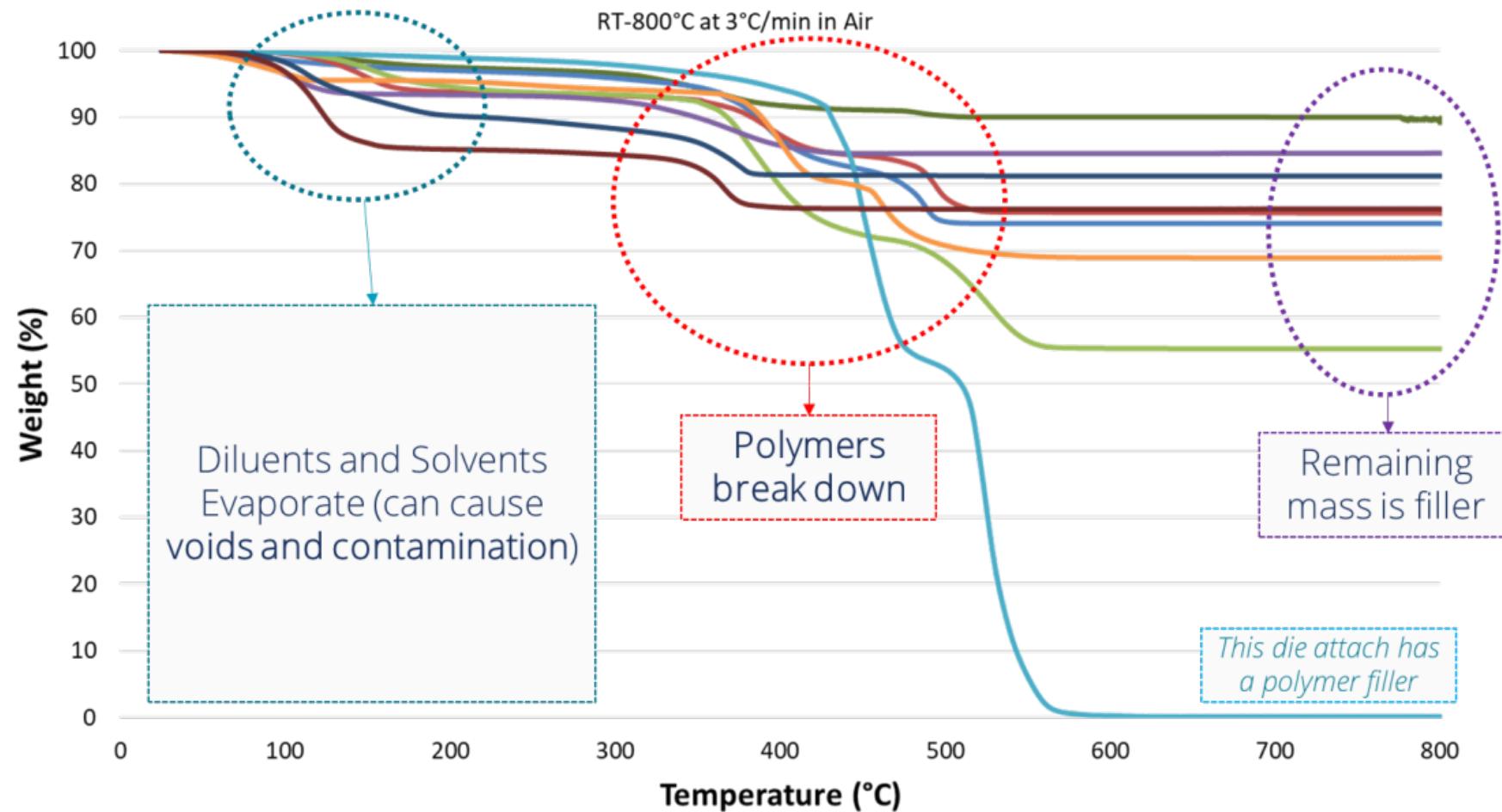
# Die Attach Materials Characterization



# Thermal Stability

Measured by thermal gravimetric analysis (TGA)

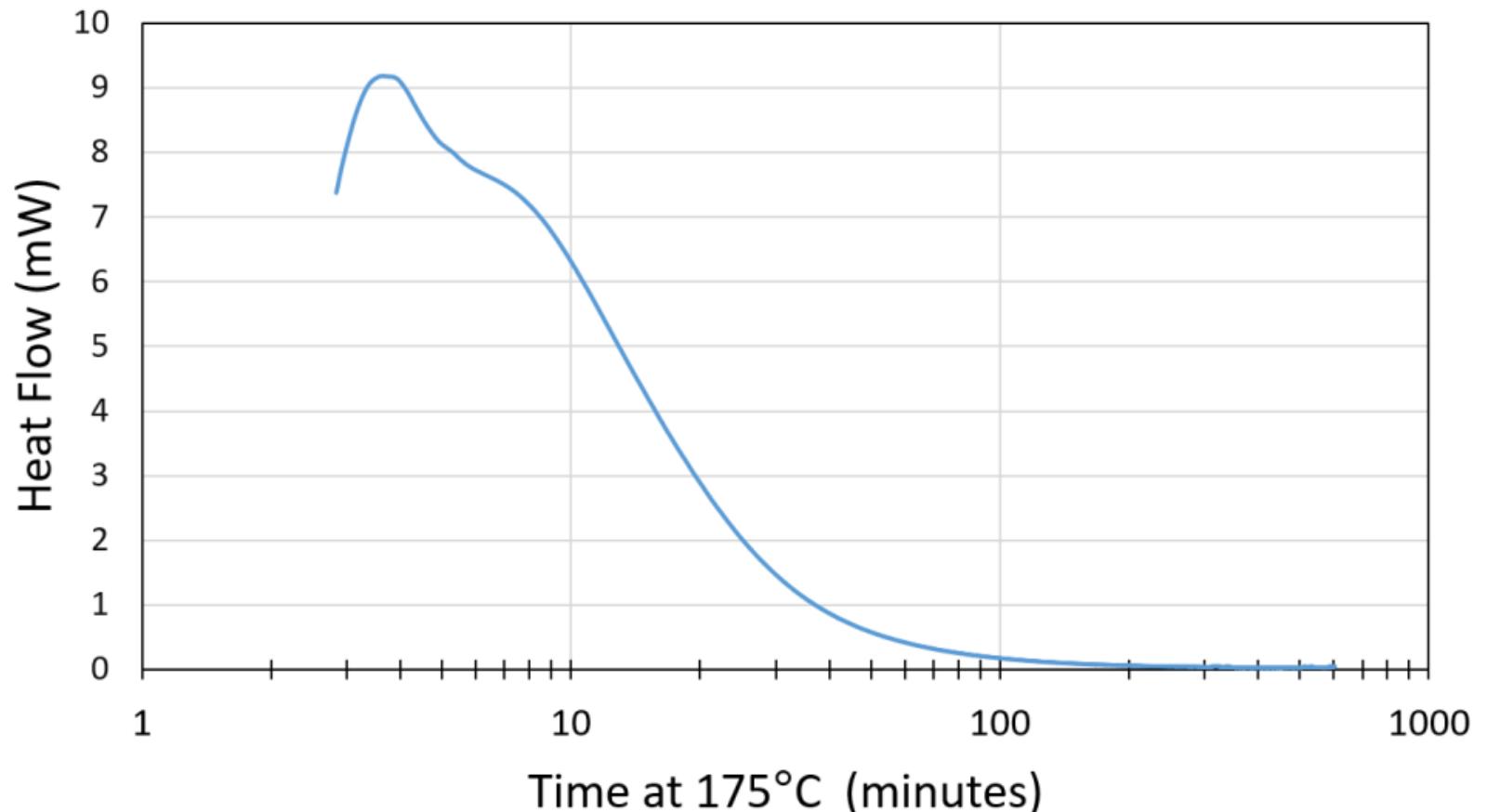
- TGA Q5000
- Heating rate of 3°C/min under air
- Jamie Kropka and Catherine Groves
- bleed



*How do high temperatures affect die attach materials, possibly impacting device reliability and performance?*

# Cure Time at Temperature

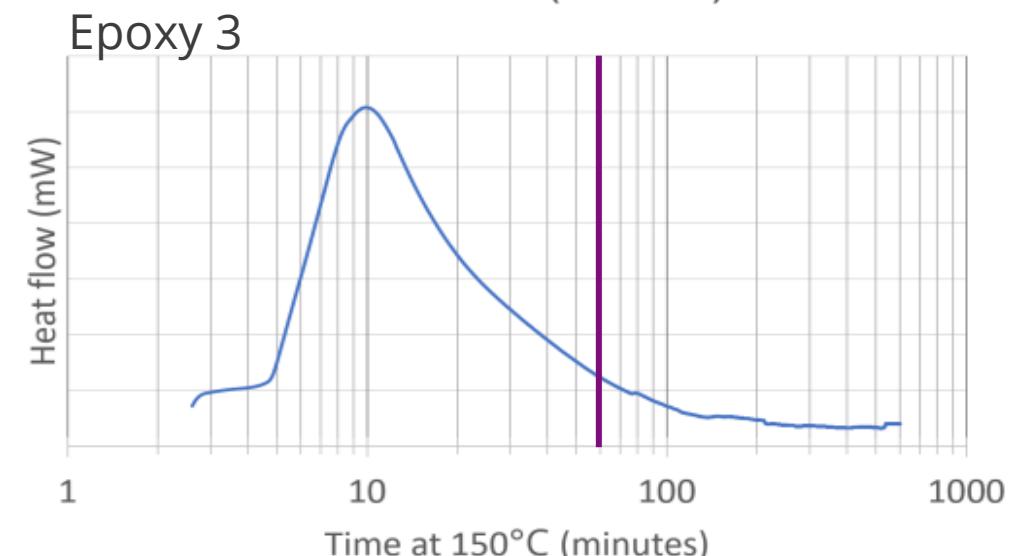
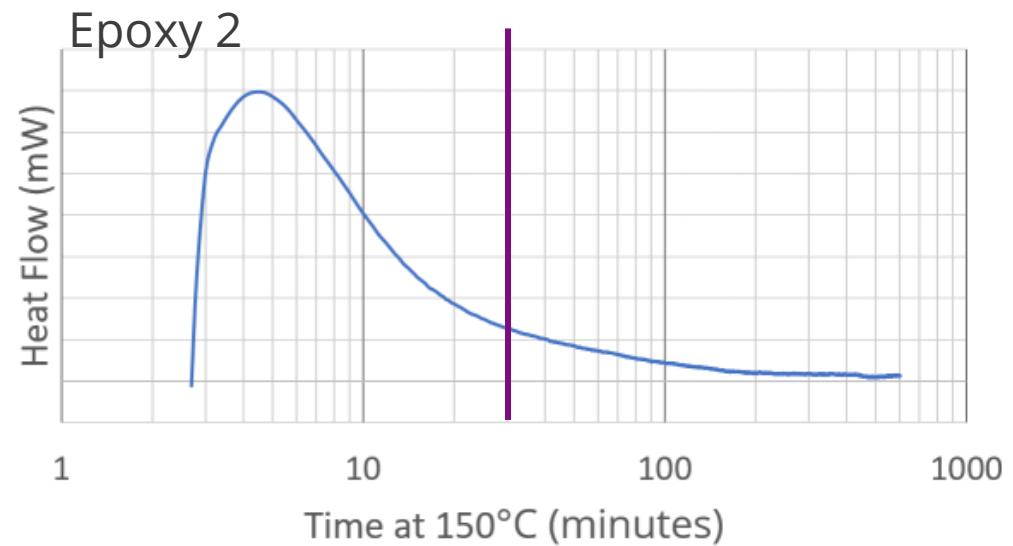
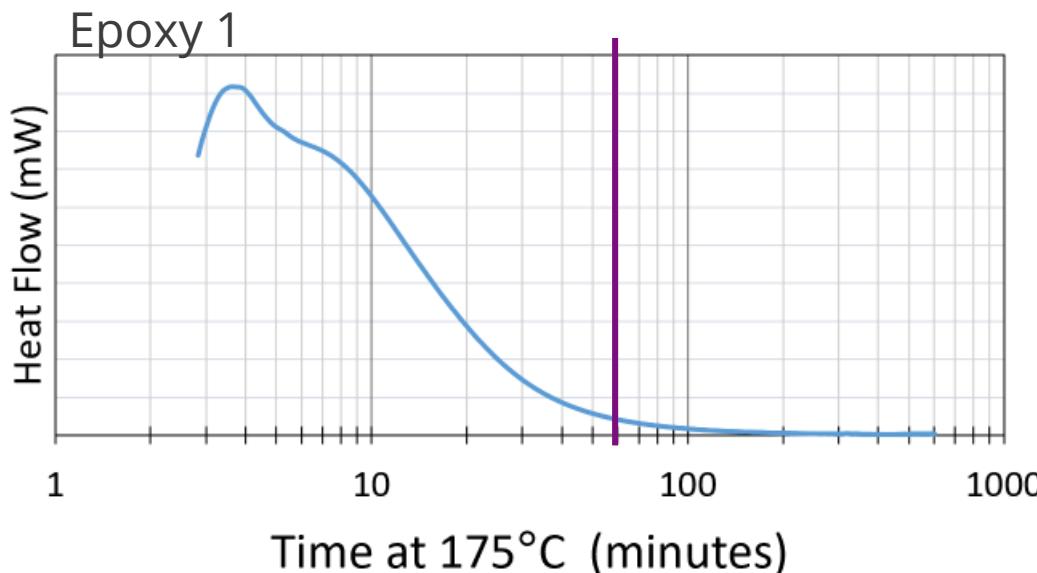
- Isothermal hold at the supplier's recommended cure temperature
- Exotherm is evidence of chemical reaction
- Measured by Differential Scanning Calorimetry (DSC)



TA Instruments Q2000 series DSC  
Jamie Kropka and Catherine Groves

# Cure Time- Data Sheet vs Complete Cure

- Data sheet cure time recommendations often under-cure the epoxy
- Data sheet recommended cure times are shown with purple lines



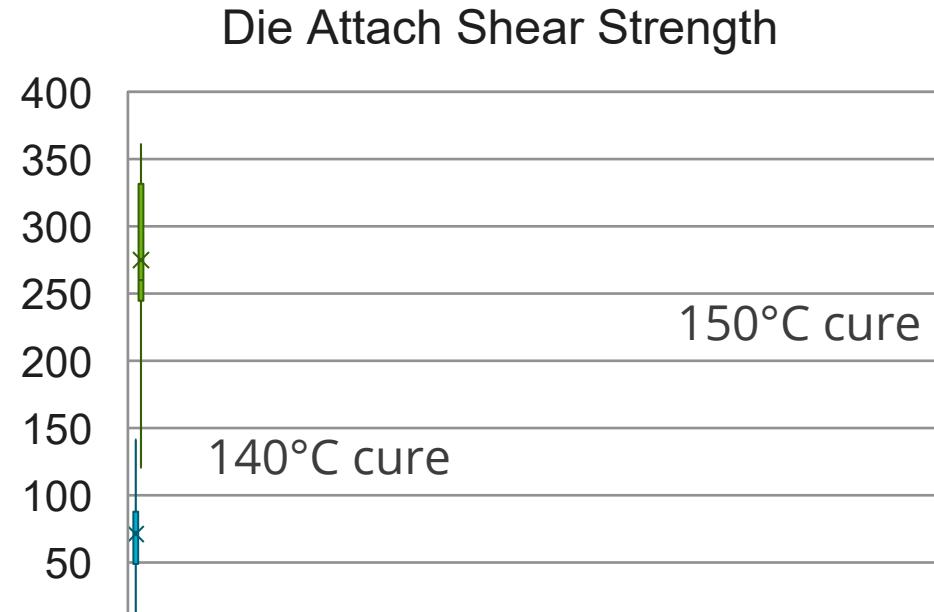
# Cure Conditions Can Affect Properties

Outgassing performance can improve with higher cure temperature

Cure Temperature	Total Mass Loss (Outgassing ASTM E595)
60 C	1.18
71 C	0.91
80 C	0.8

Thermal conductivity of silver-filled die attach often will increase as cure temperature increases

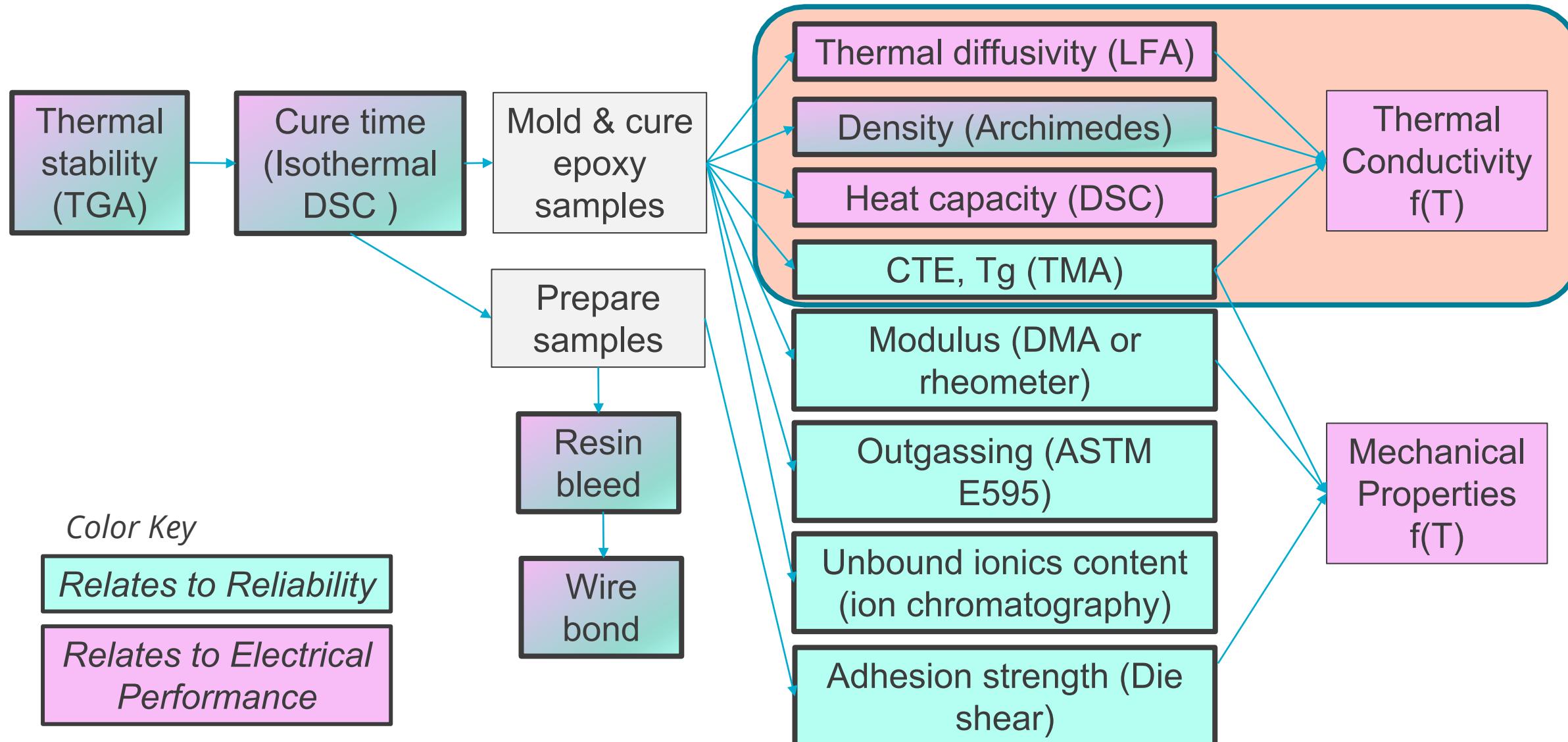
Same epoxy – Different cure



Connor Healey, Dage 4000 die shear tester

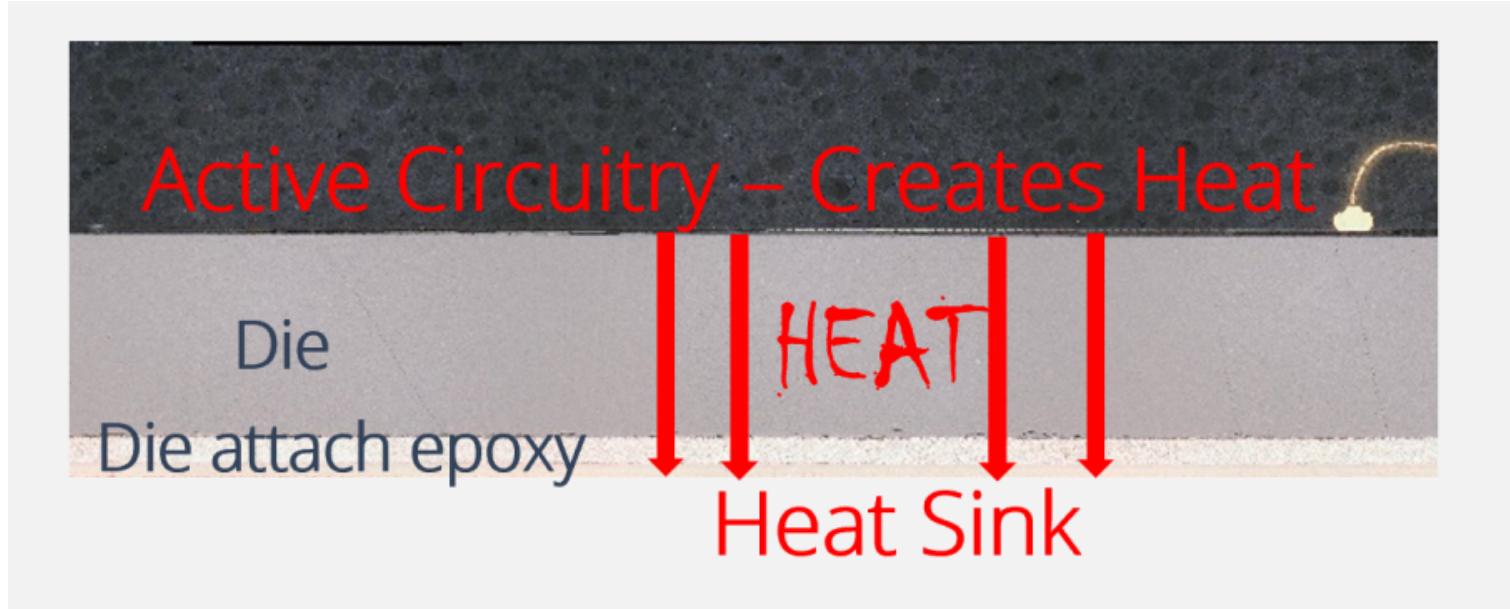
*Die attach properties can depend on the cure process*

# Die Attach Materials Characterization



# Thermal Conductivity

- Heat generated by the active circuitry of the die can transfer through the die attach

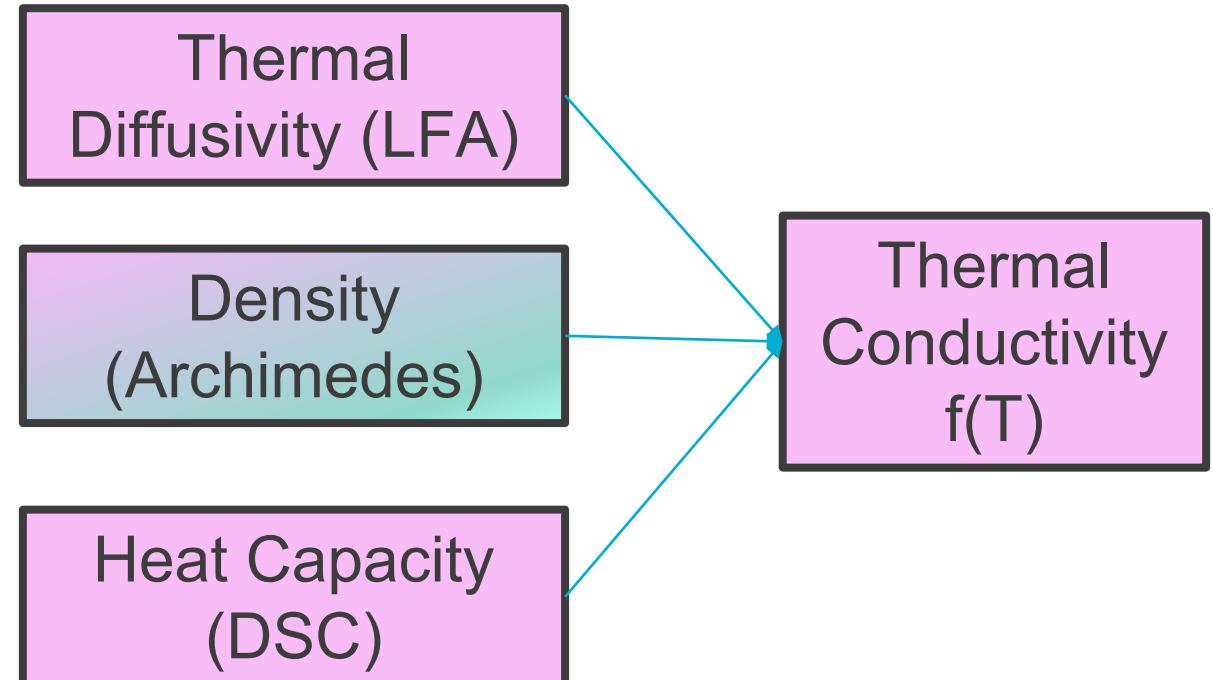


*Thermally conductive die attach can remove excess heat and lowers junction temperatures*

# Thermal Conductivity Measurement

$$\lambda = \alpha C_p \rho$$

$\lambda$	Thermal conductivity
$\alpha$	Thermal diffusivity
$C_p$	Specific Heat Capacity
$\rho$	Density

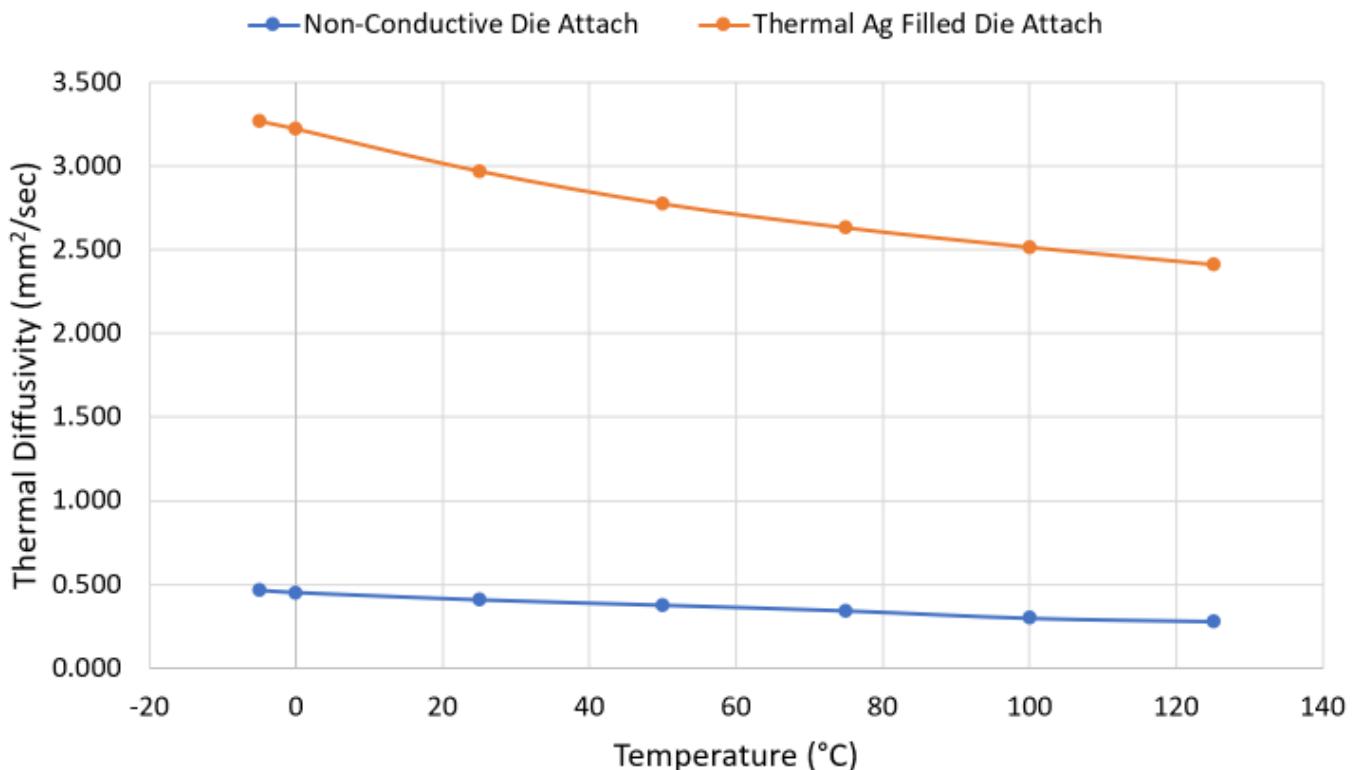


# Thermal Diffusivity Measurement



$$\lambda = \alpha C_p \rho$$

$\alpha$  Thermal diffusivity



Netzsch LFA 467 Hyperflash  
Pin Yang and Mia Blea



Designation: E1461 – 13 (Reapproved 2022)

## Standard Test Method for Thermal Diffusivity by the Flash Method<sup>1</sup>

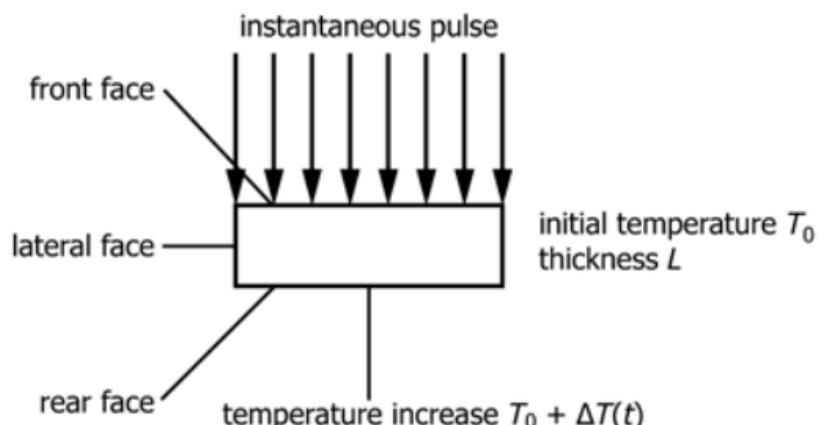


FIG. 2 Schematic of the Flash Method

# Specific Heat Measurement

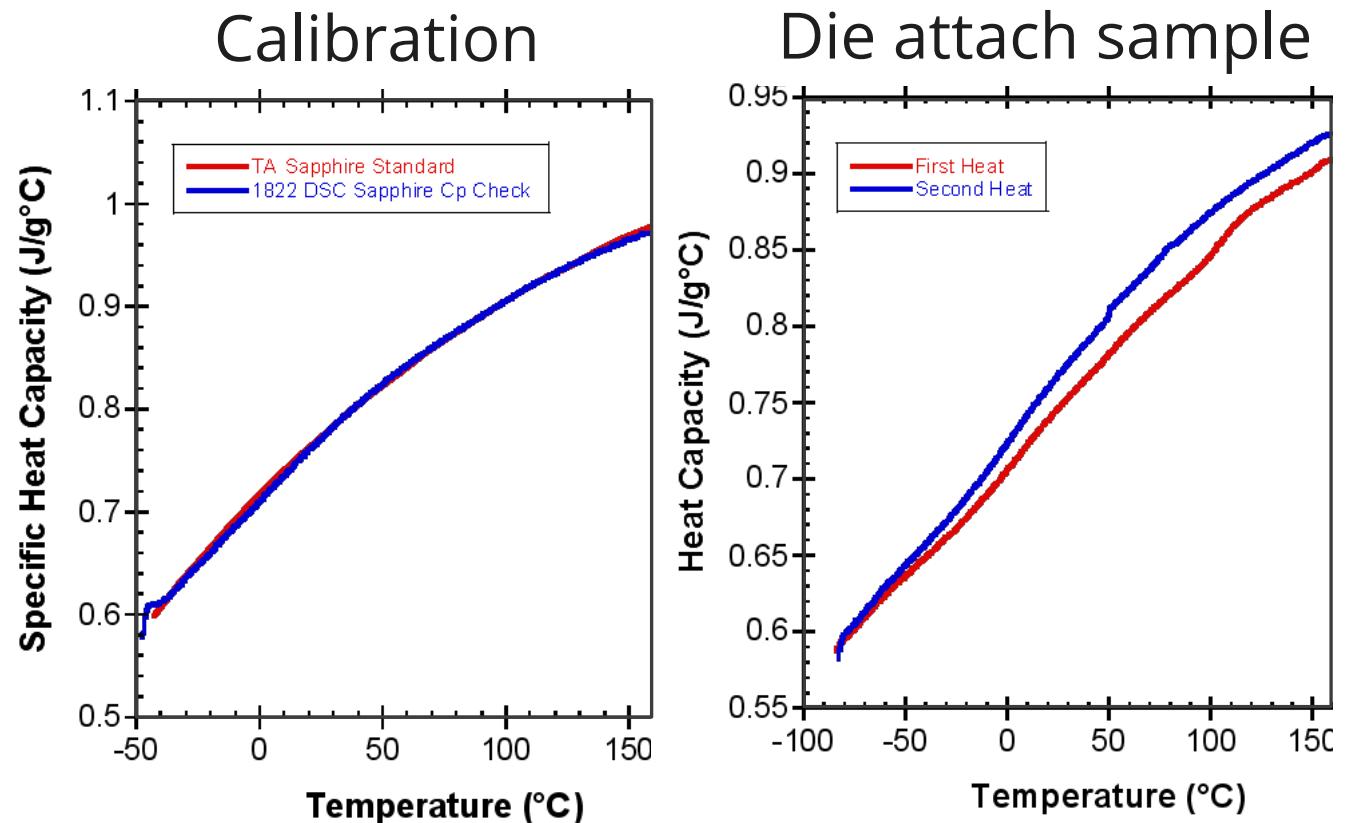
$$\lambda = \alpha C_p \rho$$

$C_p$  Specific Heat Capacity



Designation: E1269 – 11 (Reapproved 2018)

**Standard Test Method for  
Determining Specific Heat Capacity by Differential Scanning  
Calorimetry<sup>1</sup>**

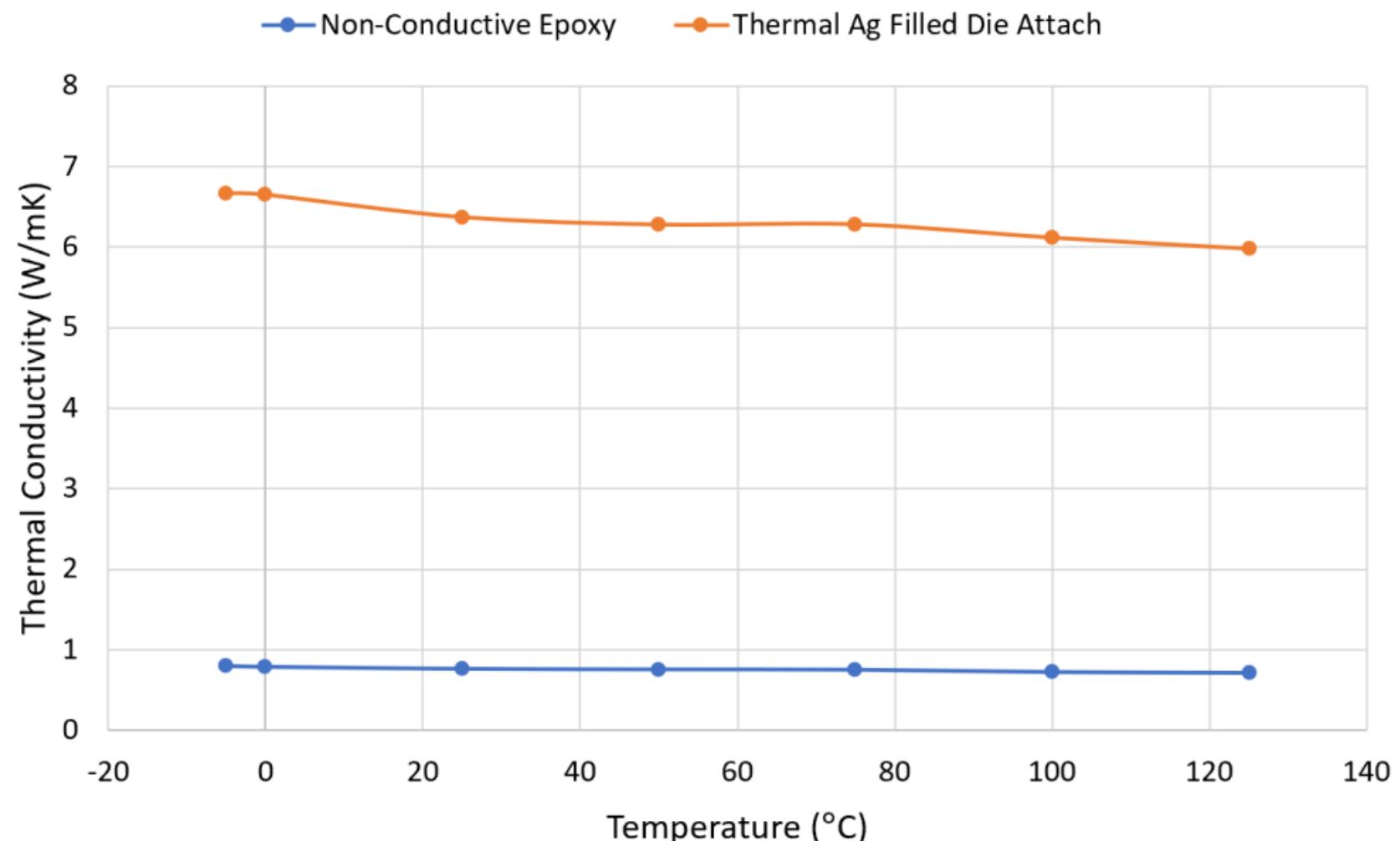


- TA Instruments Q2000 series DSC
- Performed with nitrogen sealed hermetic pans
- Jamie Kropka and Catherine Groves

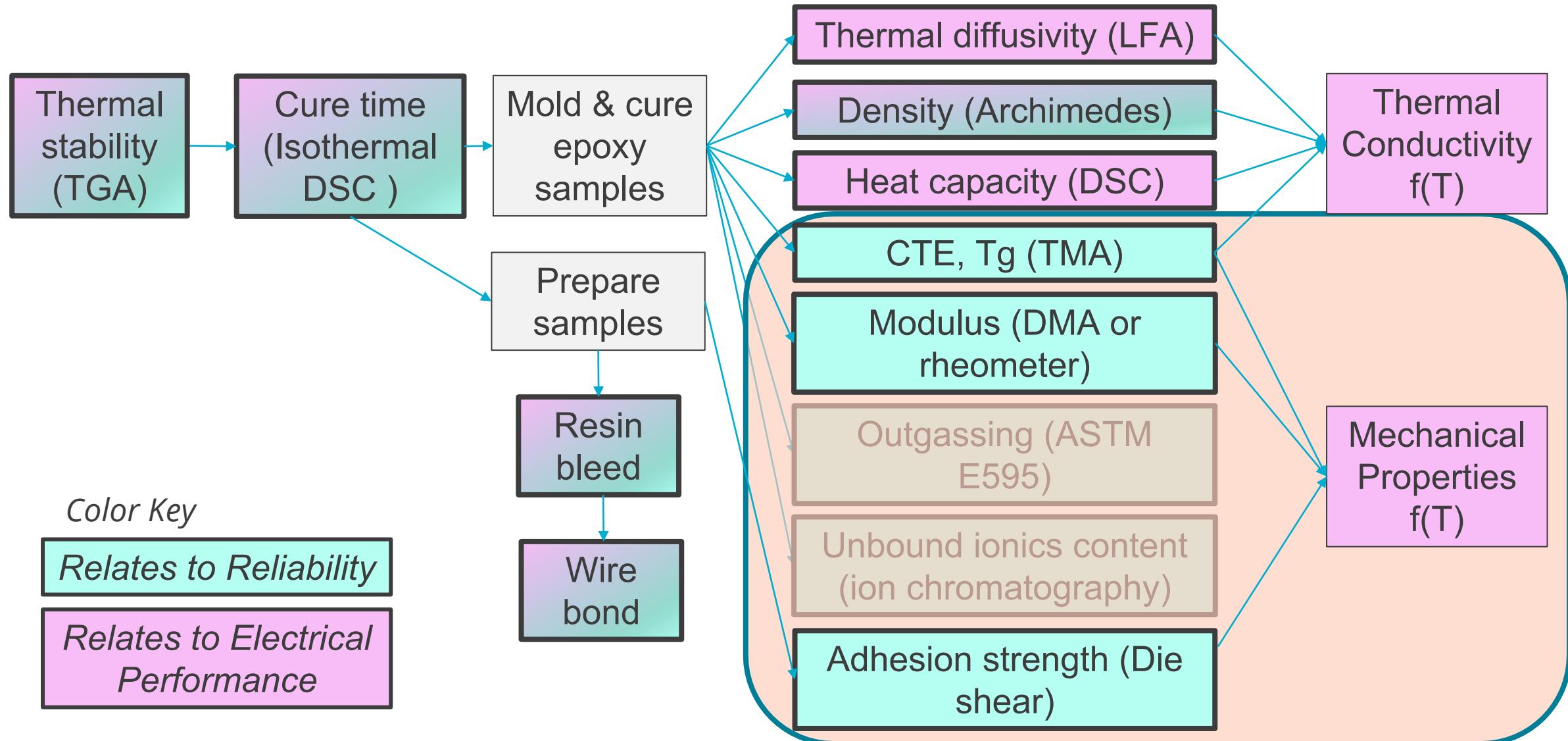
# Thermal Conductivity

$$\lambda = \alpha C_p \rho$$

$\lambda$  Thermal conductivity



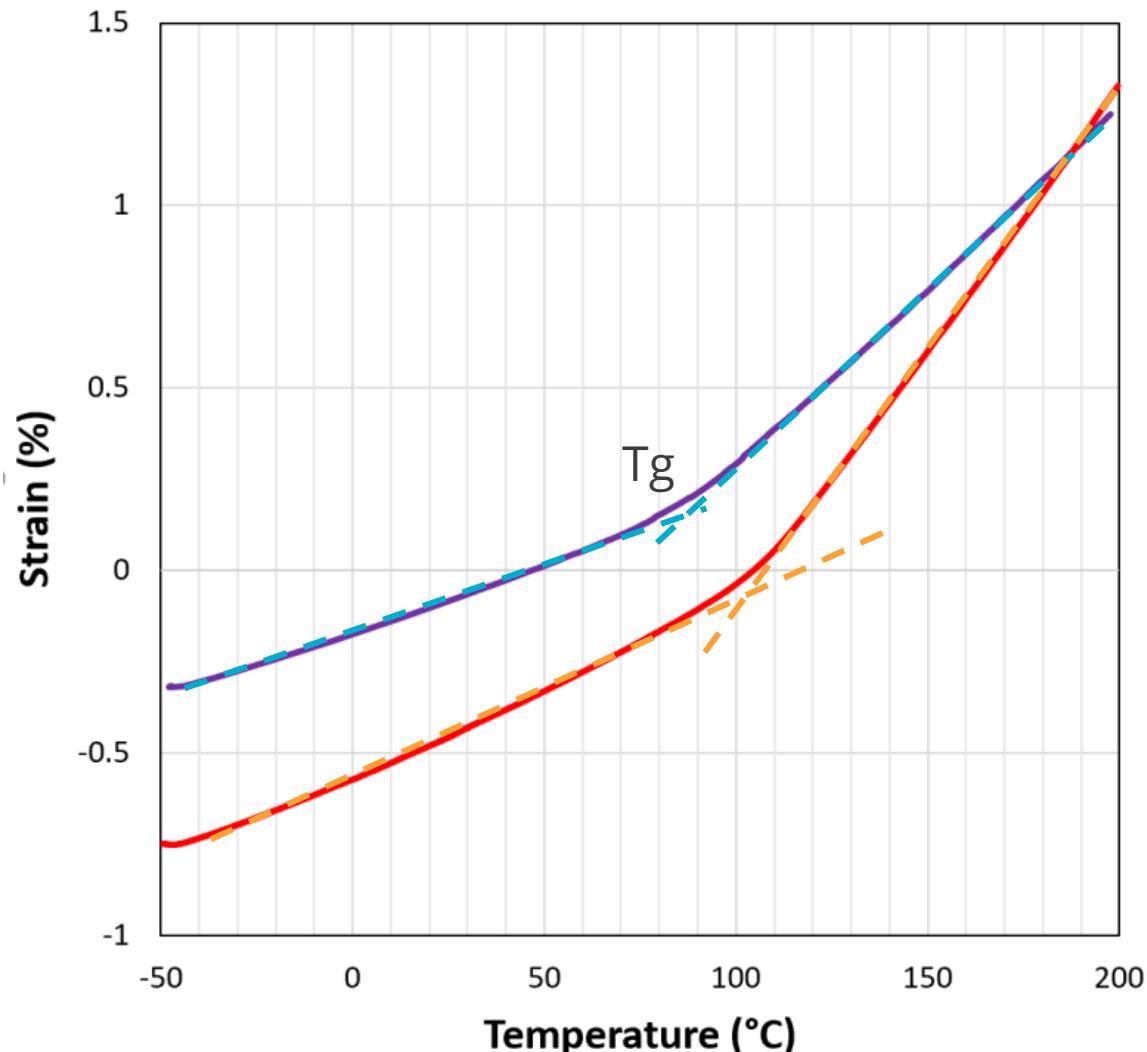
# Die Attach Materials Characterization



# Mechanical Properties – Coefficient of Thermal Expansion

## Thermal Mechanical Analysis (TMA)

- Measures the sample during heating and cooling
- Thermal expansion coefficient (slope)
- Glass transition temperature ( $T_g$ ) (inflection point)
- Shrinkage due to additional thermal excursions after cure

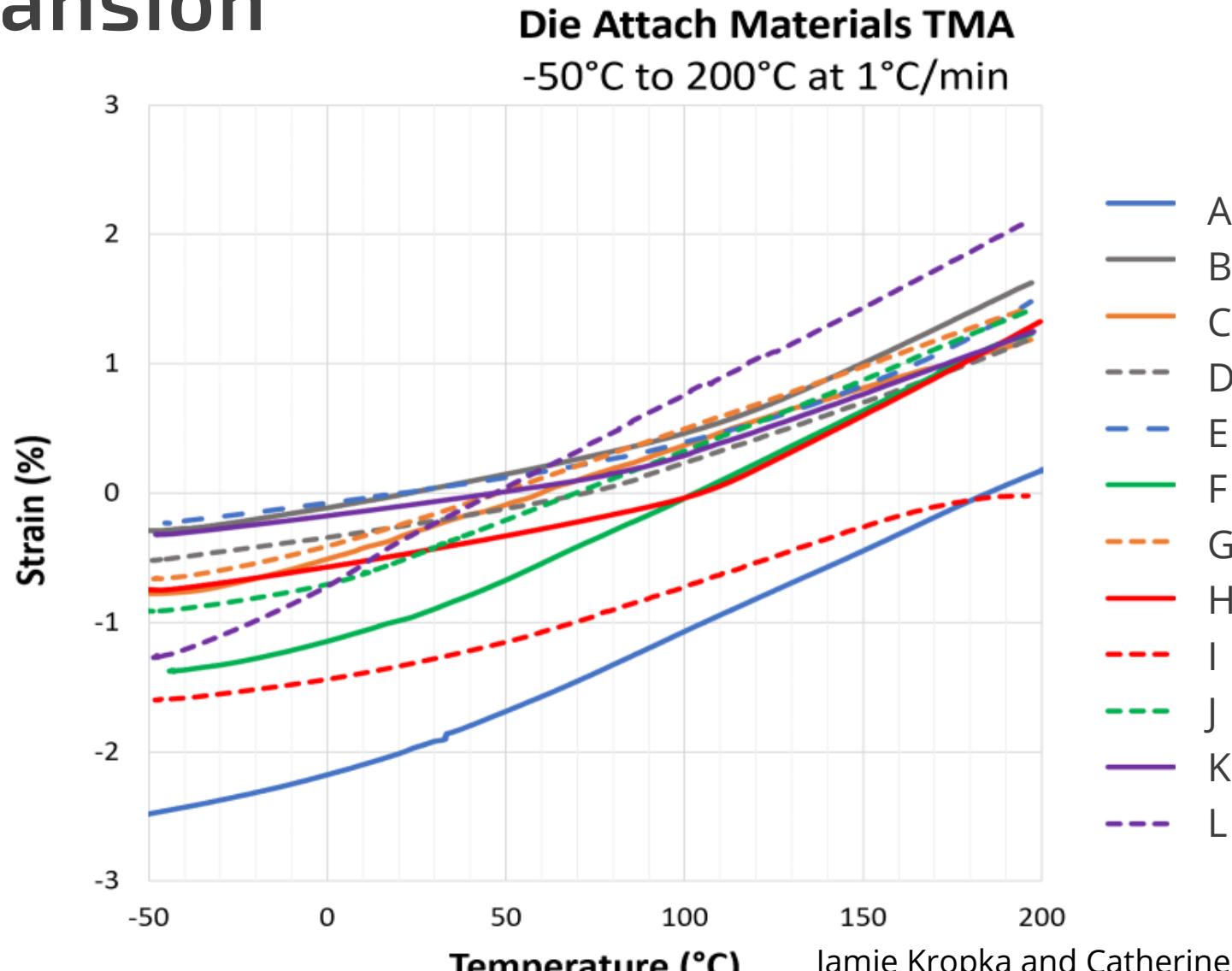


Jamie Kropka and Catherine Groves  
Heating rate of 1°C/min in nitrogen

# Mechanical Properties – Coefficient of Thermal Expansion



- Generally, lower thermal expansion is better for reliability
- Thermal expansion coefficient is part of the stress picture, but not all of it



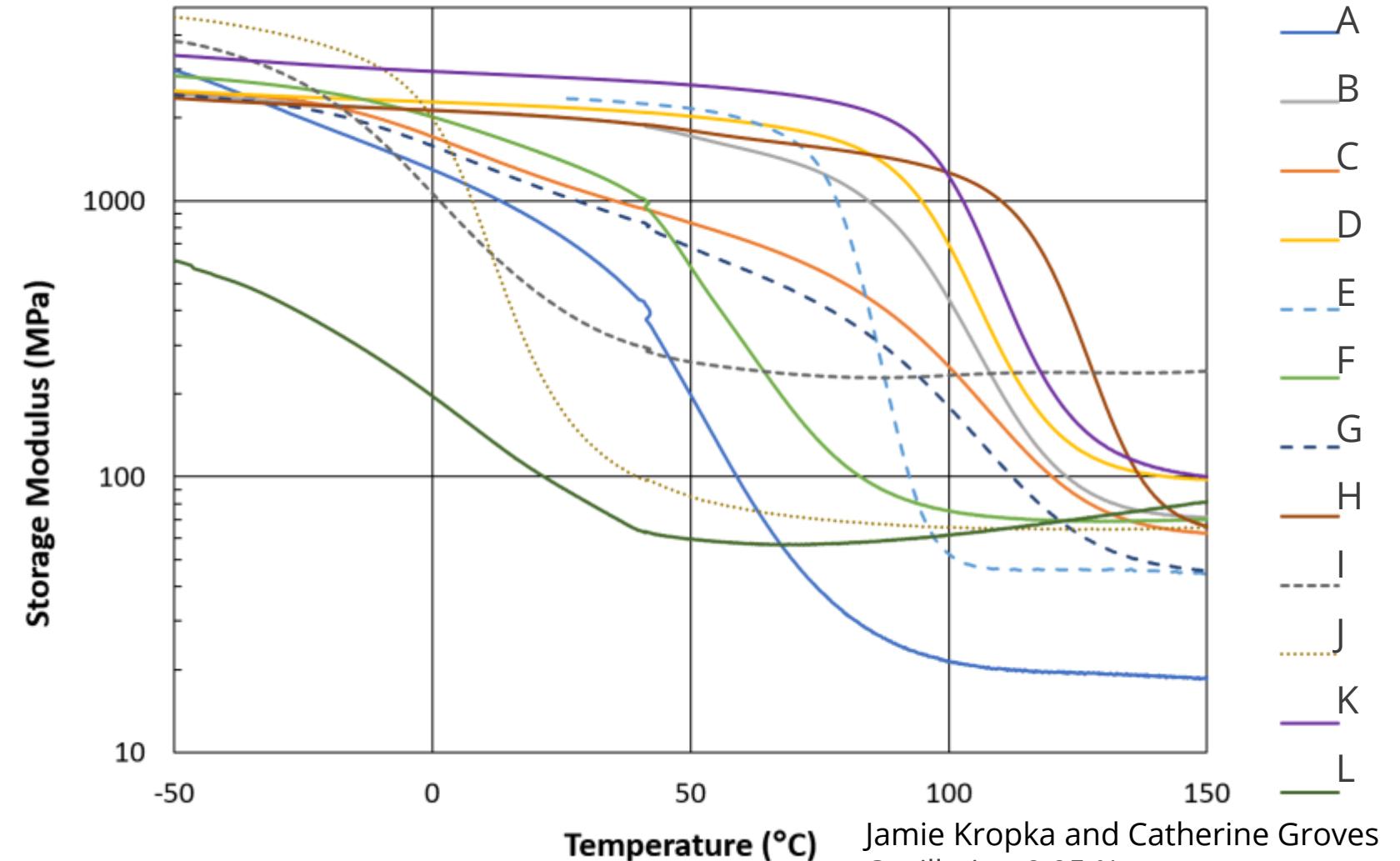
Jamie Kropka and Catherine Groves  
Heating rate of 1°C/min in nitrogen

# Mechanical Properties – Modulus



## Equipment:

- ARES G2 torsional rheometer
- This technique measures shear storage modulus, not Young's modulus
- High modulus materials are stiff
- Low modulus materials are more flexible



Jamie Kropka and Catherine Groves  
Oscillation 0.05 %



# Conclusions

Die attach material selections depend on the requirements of the system

- Material selections can affect reliability, manufacturability, and device functionality
- Characterization of critical properties improves predictive modelling fidelity versus data sheet values

To enable informed epoxy selection

- Start with the system requirements
- Derive material requirements from system requirements
- Use properties data that are trusted
- Understand that cure profile affects the die attach properties, and that data sheets often understate cure times



# Thank You!!

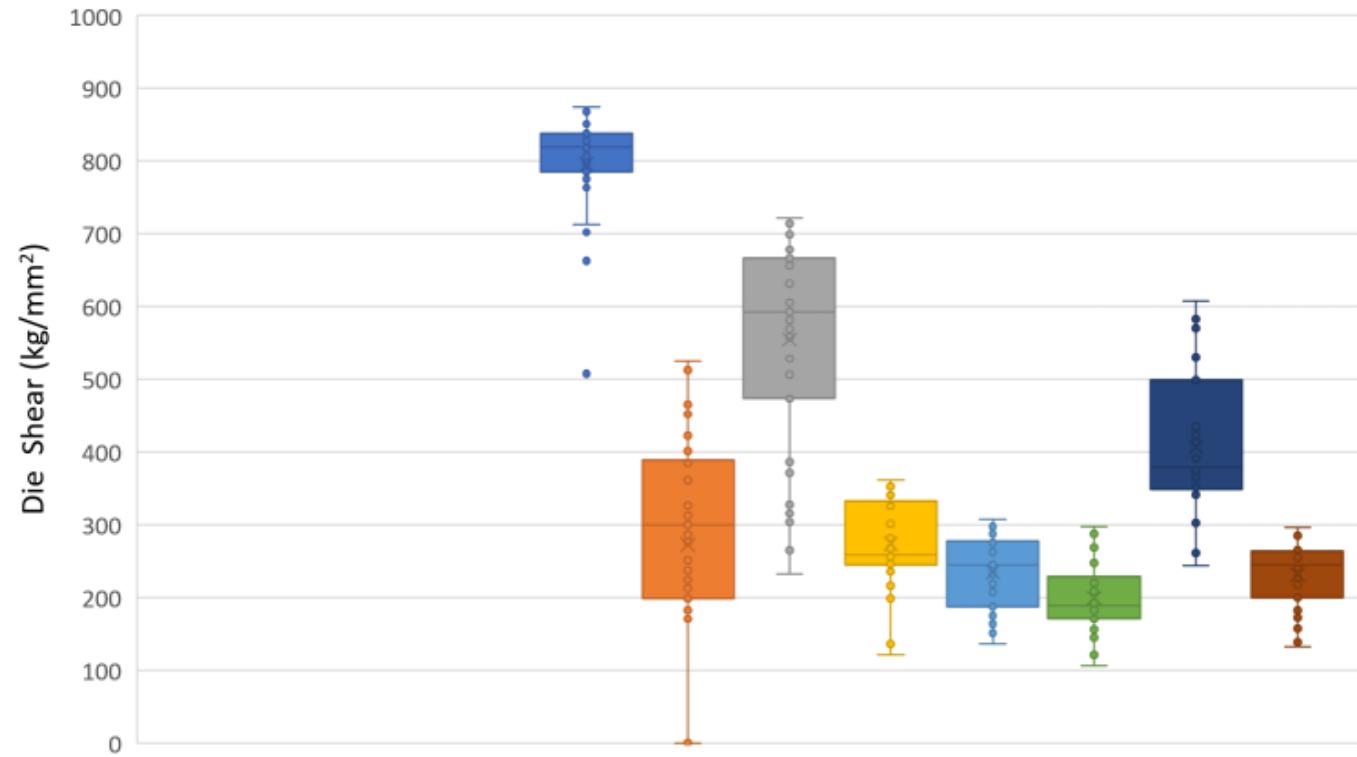
- We couldn't have done this work without you!
  - Mia Blea
  - Don Bradley
  - Shianne Carroll
  - Adrian Casias
  - Catherine Groves
  - Alvin Ha
  - Randy Hamm
  - Connor Healey
  - Jason James
  - Jamie Kropka
  - Erica McCready
  - Nalini Melon
  - Jason Tillotson
  - Daren Whitlock
  - Pin Yang

Speaker contact info: [dahagen@sandia.gov](mailto:dahagen@sandia.gov)

# Backup Slides



# Die Shear Testing



Dage 4000, Connor Healey

*Adhesion to different surfaces, cure schedule, cleanliness, and many other things affect die shear strength*